

Anomaly Detection in Images

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Objective

- Automate anomaly detection in images
 - Identify images that contain anomalies
 - Identify locations of anomalies in images

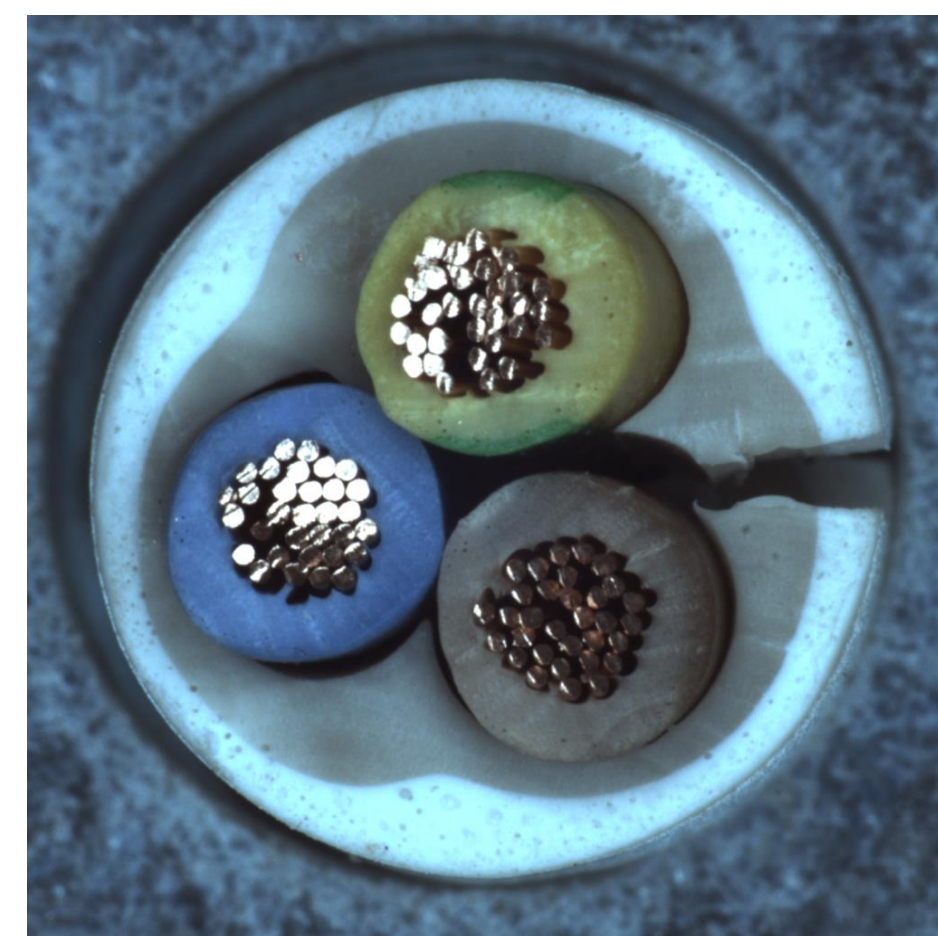


Image of cable with a cut in the outer insulation from the MVTEC dataset

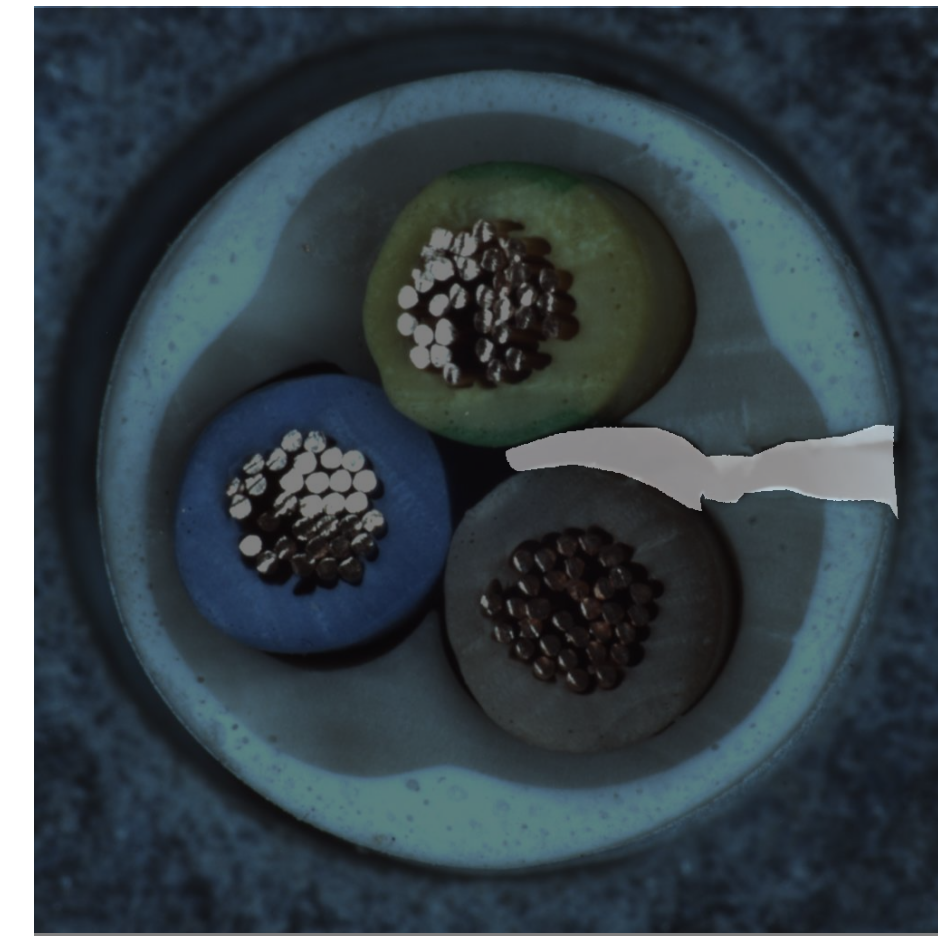
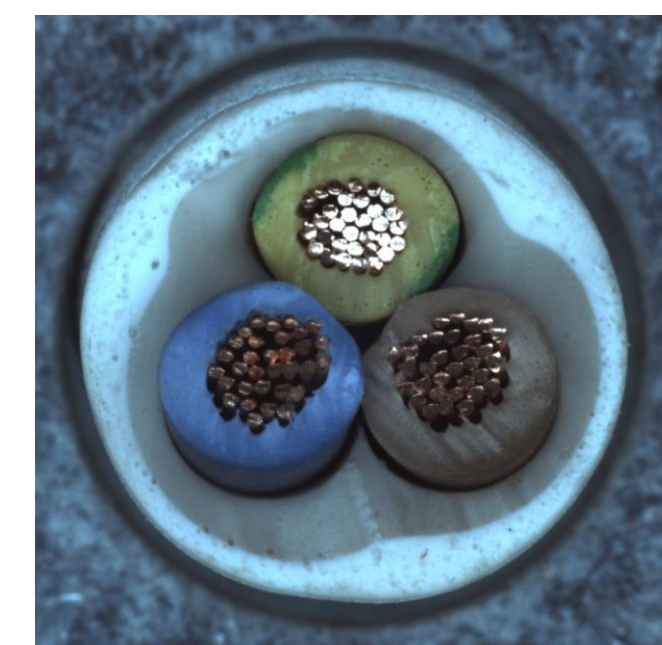


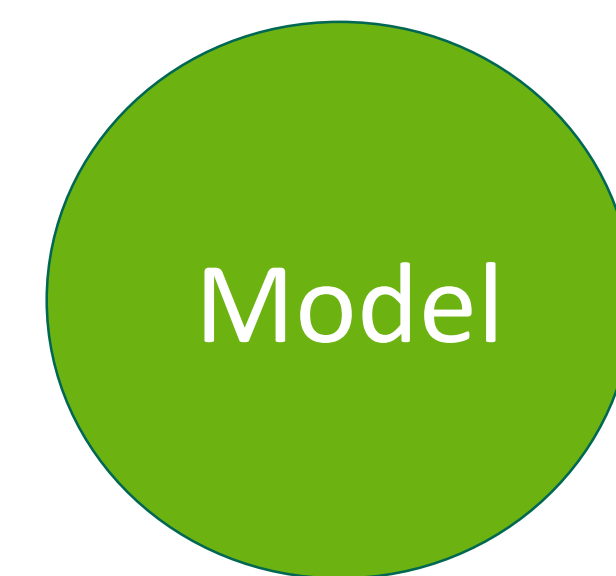
Image of cable with a cut in the outer insulation from the MVTEC dataset with mask showing the location of the anomaly

Anomaly Detection Method

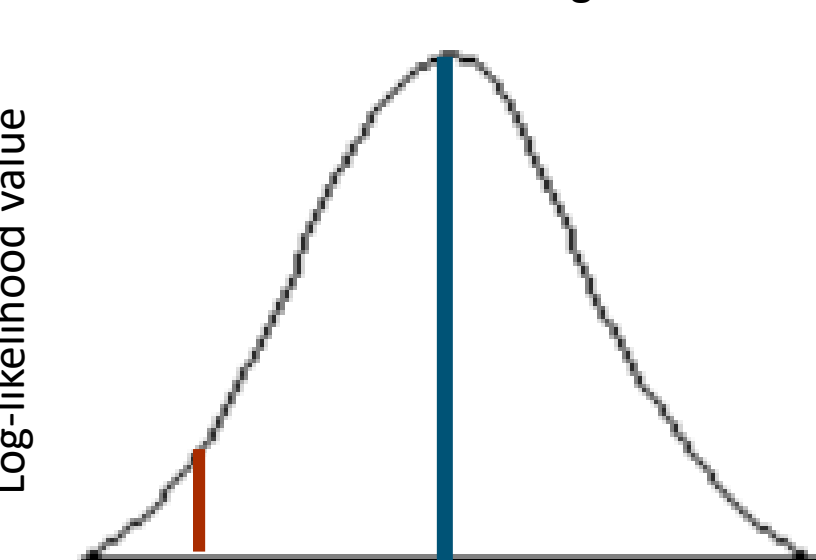
- Train a generative model to represent the probability density function of a **non-anomalous** image distribution



Non-anomalous image of a cable from the MVTEC dataset



Probability Density Function of Non-Anomalous Cable Image Distribution



Input image (red – out-of-distribution input; blue – in-distribution input)

- Query the probability density function with non-anomalous and anomalous images and compare their log-likelihood values

Anomalous Images:

- Out-of-distribution
- Low log-likelihood value

Non-Anomalous Images:

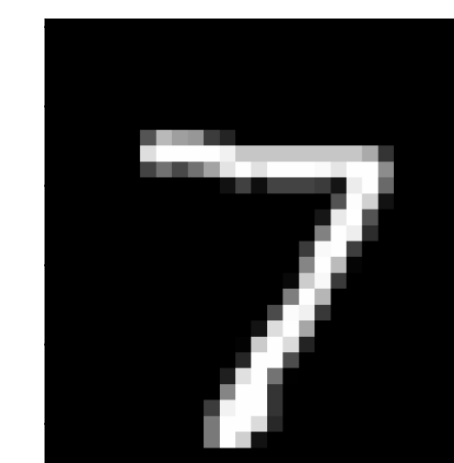
- In-distribution
- High log-likelihood value

Works Cited

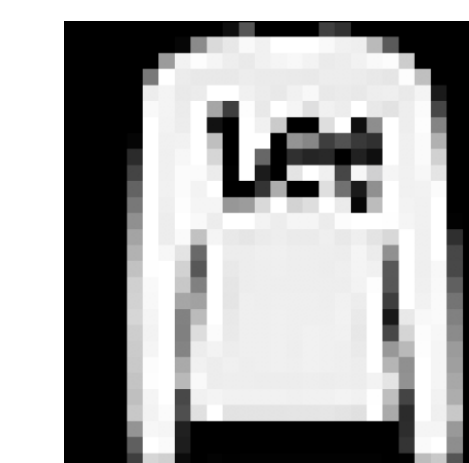
Ren, J. et al. (2019). Likelihood Ratios for Out-of-Distribution Detection. Retrieved July 13, 2020 from <https://arxiv.org/pdf/1906.02845.pdf>.
<https://www.mvtec.com/company/research/datasets/mvtec-ad/>
<https://machinelearningmastery.com/how-to-develop-a-convolutional-neural-network-from-scratch-for-mnist-handwritten-digit-classification/>

Problem

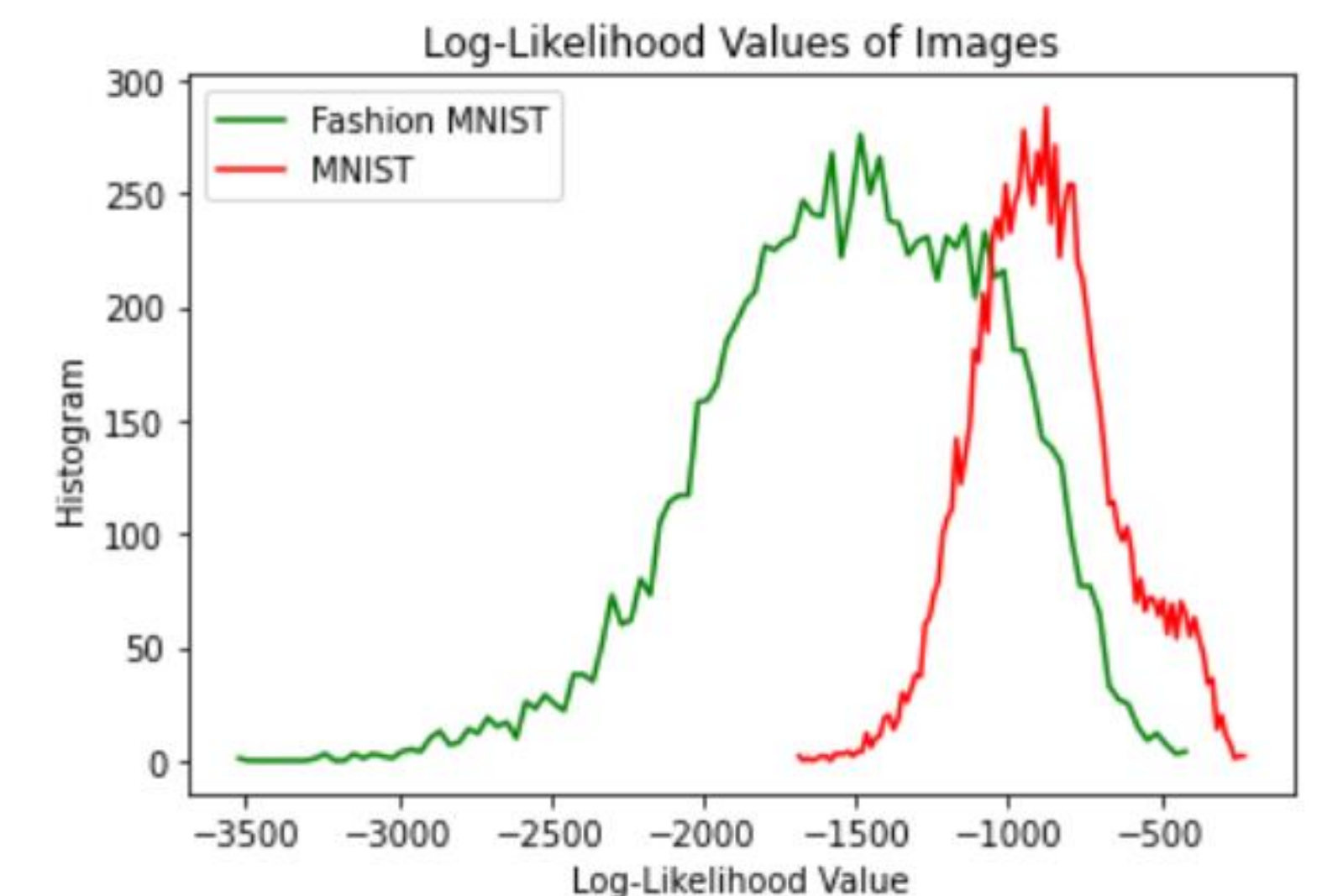
- After training the model on non-anomalous images (Fashion-MNIST), anomalous images (MNIST) are being assigned higher log-likelihood values than non-anomalous images
- Backgrounds between anomalous and non-anomalous images are similar – **dominates** the log-likelihood value



Sample image from MNIST dataset



Sample image from Fashion-MNIST dataset



Log-Likelihood Ratio Method

- Train **two** generative models for the:
 - non-anomalous, un-mutated** image distribution
 - non-anomalous, mutated** image distribution

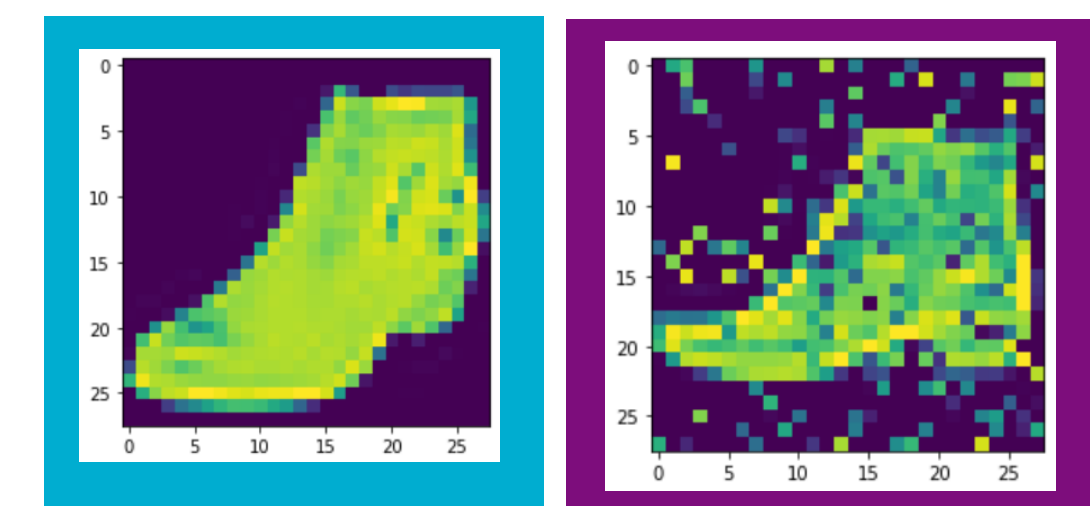
- Compare log-likelihood values, which is the product of:

- Background log-likelihood value ($p_{\theta}(x_R)$)
- Semantic log-likelihood value ($p_{\theta}(x_S)$)

- Since the background is dominant, the mutation **does not** affect the background log-likelihood value

- Therefore, the **ratio** between the un-mutated (θ) and mutated (θ_0) log-likelihood values cancels out the background log-likelihood value – only the semantic log-likelihood ratio is considered

Log-likelihood ratio score:
 High = in-distribution (Fashion-MNIST)
 Low = out-of-distribution (MNIST)

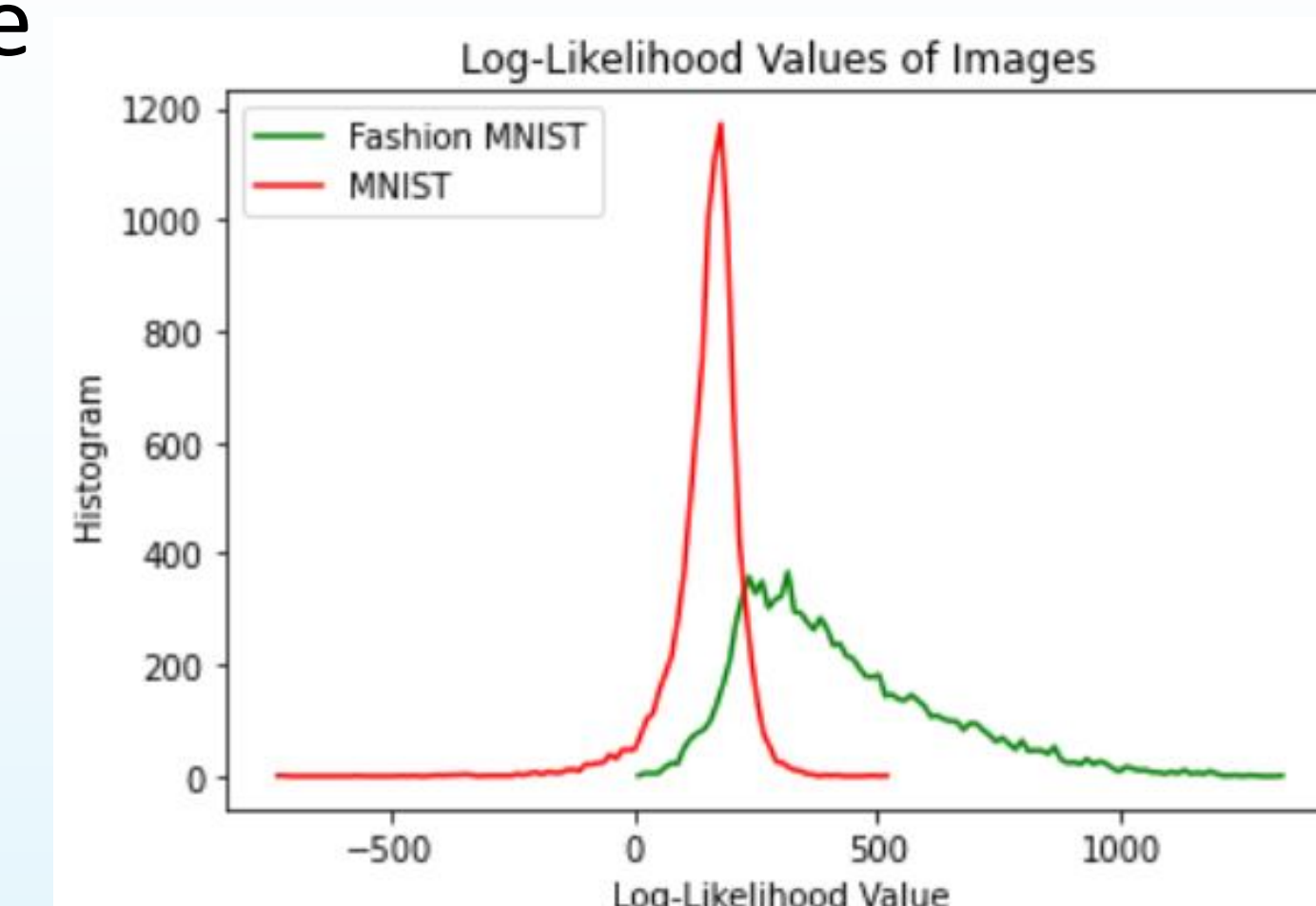


Non-anomalous, un-mutated image

Non-anomalous, mutated image

$$LLR(x) = \log \frac{p_{\theta}(x_B) p_{\theta}(x_S)}{p_{\theta_0}(x_B) p_{\theta_0}(x_S)}$$

Log-likelihood ratio value calculation – since the background log-likelihood value is cancelled out, only the ratio between the semantic log-likelihood values is considered



Application

- Given images or CT scans of high-reliability materials, can provide reliable automated anomaly detection